

# N-Channel 60 V(D-S) MOSFET

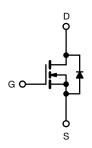
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	60				
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V 0.072				
Q <sub>g</sub> max. (nC)	25				
Q <sub>gs</sub> (nC)	5.8				
Q <sub>gd</sub> (nC)	11				
Configuration	Single				

#### **FEATURES**

- Dynamic dV/dt rating
- Fast switching
- Ease of paralleling Simple drive requirements







N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	60	V	
Gate-Source Voltage			$V_{GS}$	± 20	1 v	
Continuous Drain Current	T <sub>C</sub>	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	I <sub>D</sub>	20	А	
	V <sub>GS</sub> at 10 V	$T_{\rm C} = 100 ^{\circ}{\rm C}$		12		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	68		
Linear Derating Factor				0.40	W/°C	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	100	mJ	
Maximum Power Dissipation T <sub>C</sub> = 25 °C			$P_{D}$	60	W	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C	
Soldering Recommendations (Peak temperature) d	for 10 s			300		
Manustin a Taurus	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD}$  = 25 V, starting  $T_J$  = 25 °C, L = 403  $\mu$ H,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 17 A (see fig. 12).
- c.  $I_{SD} \leq 17$  A,  $dI/dt \leq 140$  A/µs,  $V_{DD} \leq V_{DS}$ ,  $T_{J} \leq 175$  °C.
- d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62			
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.50	-	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	2.5			

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static				L			1
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA		-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I <sub>D</sub> = 1 mA		0.061	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	· V <sub>GS</sub> , I <sub>D</sub> = 250 μA	1.0	-	3.0	V
Gate-Source Leakage	I <sub>GSS</sub>	,	$V_{GS} = \pm 20 \text{ V}$		-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		= 60 V, V <sub>GS</sub> = 0 V , V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V		-	0.072	-	Ω
Forward Transconductance	9 <sub>fs</sub>		= 25 V, I <sub>D</sub> = 10 A	5.5	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V$ ,		-	640	-	
Output Capacitance	C <sub>oss</sub>		$V_{DS} = 25 \text{ V},$	-	360	-	рF
Reverse Transfer Capacitance	$C_{rss}$	f = 1.	0 MHz, see fig. 5	-	79	-	
Total Gate Charge	$Q_g$			-	-	25	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 17 \text{ A}, V_{DS} = 48 \text{ V},$ see fig. 6 and 13 b		-	5.8	nC
Gate-Drain Charge	Q <sub>gd</sub>	1	3	-	-	11	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = 30 V, $I_{D}$ = 17 A, $R_{g}$ = 18 $\Omega$ , $R_{D}$ = 1.7 $\Omega$ , see fig. 10 <sup>b</sup>		-	13	-	- ns
Rise Time	t <sub>r</sub>			-	58	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	25	-	
Fall Time	t <sub>f</sub>			-	42	-	
Internal Drain Inductance	L <sub>D</sub>	6 mm (0.25") t	Between lead, 6 mm (0.25") from		4.5	-	
Internal Source Inductance	L <sub>S</sub>	package and center of die contact		-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s				•	•	
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	20	Α
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	68	_ ^
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 17 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 17 A, dl/dt = 100 A/μs		-	88	180	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.29	0.64	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )					L <sub>D</sub> )

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300  $\mu s$ ; duty cycle  $\leq$  2 %.



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

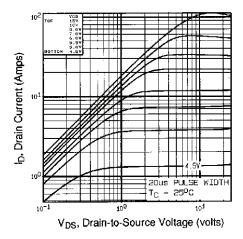


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

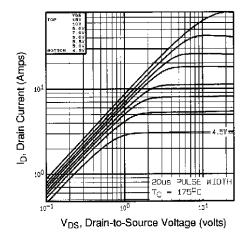


Fig. 2 - Typical Output Characteristics,  $T_C = 175$  °C

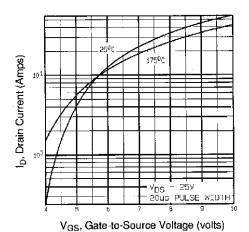


Fig. 3 - Typical Transfer Characteristics

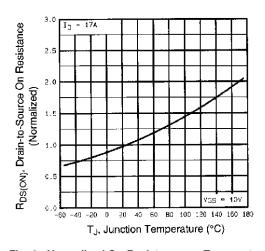


Fig. 4 - Normalized On-Resistance vs. Temperature

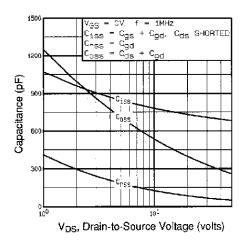


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

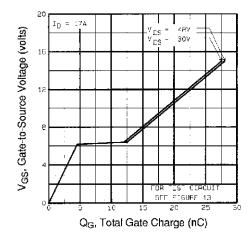


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



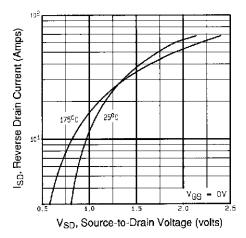


Fig. 7 - Typical Source-Drain Diode Forward Voltage

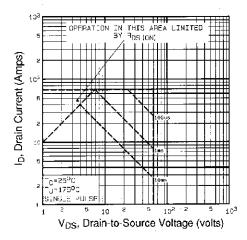


Fig. 8 - Maximum Safe Operating Area

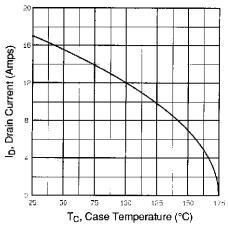


Fig. 9 - Maximum Drain Current vs. Case Temperature

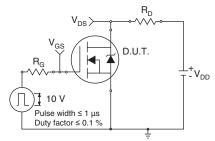


Fig. 10a - Switching Time Test Circuit

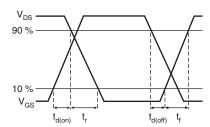


Fig. 10b - Switching Time Waveforms

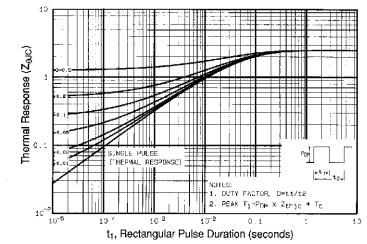
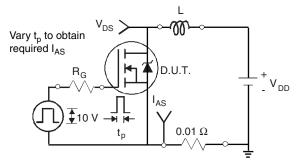


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case







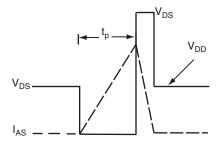


Fig. 12b - Unclamped Inductive Waveforms

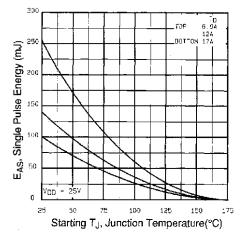


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

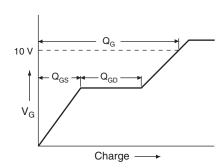


Fig. 13a - Basic Gate Charge Waveform

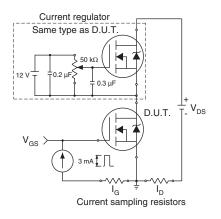
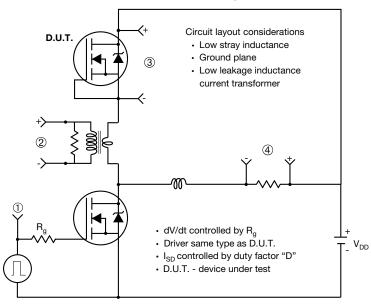


Fig. 13b - Gate Charge Test



### Peak Diode Recovery dV/dt Test Circuit



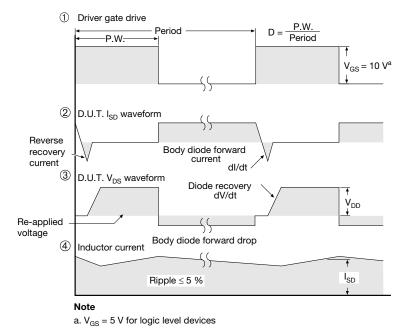
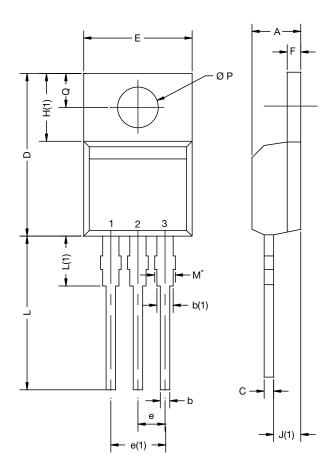


Fig. 14 - For N-Channel



## TO-220



DIM.	MILLIN	IETERS	INCHES		
DIW.	MIN.	MAX.	MIN.	MAX.	
Α	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
Е	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØР	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	
ECN: X15-0364-Rev. C, 14-Dec-15 DWG: 6031					

### Note

 $\bullet$   $M^{\star}=0.052$  inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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